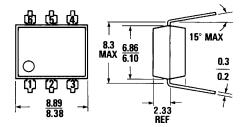
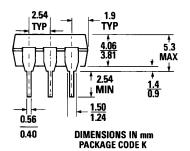


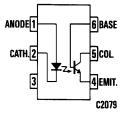
### 4N35 4N36 4N37

#### **PACKAGE DIMENSIONS**





ST1603A



Equivalent Circuit

#### **DESCRIPTION**

The 4N35, 4N36, and 4N37 series of optocouplers have an NPN silicon planar phototransistor optically coupled to a gallium arsenide infrared emitting diode.

#### **FEATURES & APPLICATIONS**

- AC line/digital logic isolator
- Digital logic/digital logic isolator
- Telephone/telegraph line receiver
- Twisted pair line receiver
- High frequency power supply feedback control
- Relay contact monitor
- Power supply monitor
- Industrial controls
- Covered under UL component recognition program, reference File E90700
- High DC current transfer ratio

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TOTAL PACKAGE	OUTPUT TRANSISTOR
*Relative humidity 85% @ 85°C	*Power dissipation at 25°C ambient 300 mW
*Storage temperature55°C to 150°C	Derate linearly above 25°C 4 mW/°C
*Operating temperature –55°C to 100°C	*Power dissipation at T <sub>c</sub> =25°C 500 mW††
*Lead temperature (soldering, 10 sec) 260°C	(T <sub>c</sub> indicates collector lead temp 1/32" from case)
INPUT DIODE	1/32 Hom case)
*Forward DC current (continuous) 60 mA	*\/
Reverse voltage 6 volts	*V <sub>CEO</sub>
*Peak forward current	*V <sub>CBO</sub> 70 volts
(1 μs pulse, 300 pps) 3.0 A	*V <sub>ECO</sub> 7 volts
*Power dissipation at T <sub>A</sub> =25°C 100 mW†	*Collector current (continuous) 100 mA
*Power dissipation at T <sub>c</sub> =25°C 100 mW†	
(T <sub>c</sub> indicates collector lead temp	
1/32" from case)	



# ELECTRO-OPTICAL CHARACTERISTICS (25°C Free Air Temperature Unless Otherwise Specified)

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
INPUT DIODE						***
*Forward voltage	V <sub>F</sub>	.8		1.50	٧	$I_F = 10 \text{ mA}$
*Forward voltage temp. coefficient	V <sub>F</sub>	.9		1.7	٧	I <sub>F</sub> =10 mA, T <sub>A</sub> =-55°C
*Forward voltage	V <sub>F</sub>	.7		1.4	٧	I <sub>F</sub> =10 mA,
						T <sub>A</sub> =+100°C
*Junction capacitance	C,			100	pF	$V_F=0 V, f=1 mHz$
*Reverse leakage current			.01	10	μΑ	$V_{R} = 6.0 \text{ V}$
DETECTOR						
DC forward current gain	$h_{\scriptscriptstyle{FE}}$		250			$V_{CE} = 5 \text{ V}, I_{C} = 100 \mu \text{A}$
*Collector to emitter breakdown voltage	BV <sub>CEO</sub>	30	65		٧	I <sub>c</sub> =10 mA, I <sub>F</sub> =0
*Collector to base breakdown voltage	ВУсво	70	165		٧	I <sub>c</sub> =100 μA, I <sub>F</sub> =0
*Emitter to collector breakdown voltage	BV <sub>ECO</sub>	7	14		٧	$I_E = 100 \mu A, I_F = 0$
Collector to emitter, leakage current	I <sub>CEO</sub>		5	50	nA	V <sub>CE</sub> =10 V, I <sub>F</sub> =0
*Collector to emitter leakage current (dark)	I <sub>CEO</sub>			500	μΑ	V <sub>CE</sub> =30 V, I <sub>F</sub> =0, T <sub>A</sub> =100°C
Capacitance collector to emitter	C <sub>CEW</sub>		8		pF	V <sub>CE</sub> =0
Capacitance collector to base	Ссво		20		pF	V <sub>CB</sub> =10 V
Capacitance base to emitter	C <sub>BEO</sub>		10		pF	V <sub>RF</sub> =0

TRANSFER CHARACTERISTICS						
CHARACTERISTICS	SYMBOL	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
COUPLED †*DC current transfer ratio	CTR	100			%	I <sub>F</sub> =10 mA, V <sub>CE</sub> =10 V
†*DC current transfer ratio	CTR	40			%	I <sub>F</sub> =10 mA, V <sub>CE</sub> =10 V, T <sub>A</sub> =-55°C
†*DC current transfer ratio	CTR	40			%	I <sub>F</sub> =10 mA, V <sub>CE</sub> =10 V, T <sub>A</sub> =+100°C
*Saturation voltage—collector to emitter	V <sub>CE(SAT)</sub>			.3	volts	I <sub>F</sub> =10 mA, I <sub>C</sub> =0.5 mA

TRANSFER CHARA	TRANSFER CHARACTERISTICS					
AC CHARACTERISTICS	SYMBOL	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
*Turn on time	t <sub>on</sub>		5	10	μsec	$V_{cc}$ =10 V, $I_c$ =2 mA, $R_c$ =100 $\Omega$ , (Fig. 10 and Fig. 11)
*Turn off time	t <sub>OFF</sub>		5	10	μsec	$V_{cc}$ =10 V, $I_c$ =2 mA, $R_c$ =100 $\Omega$ , (Fig. 10 and Fig. 11)

<sup>\*</sup>Indicates JEDEC registered values †Pulse test: pulse width=300 µS, duty cycle≤2.0%

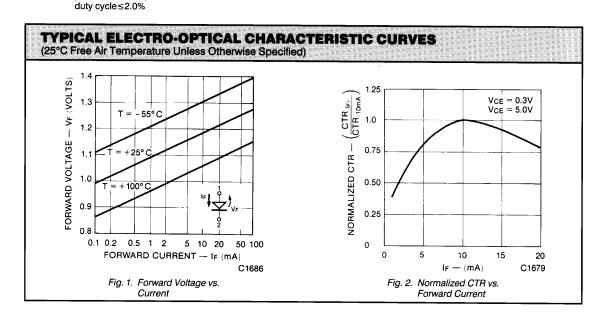


#### **ELECTRO-OPTICAL CHARACTERISTICS**

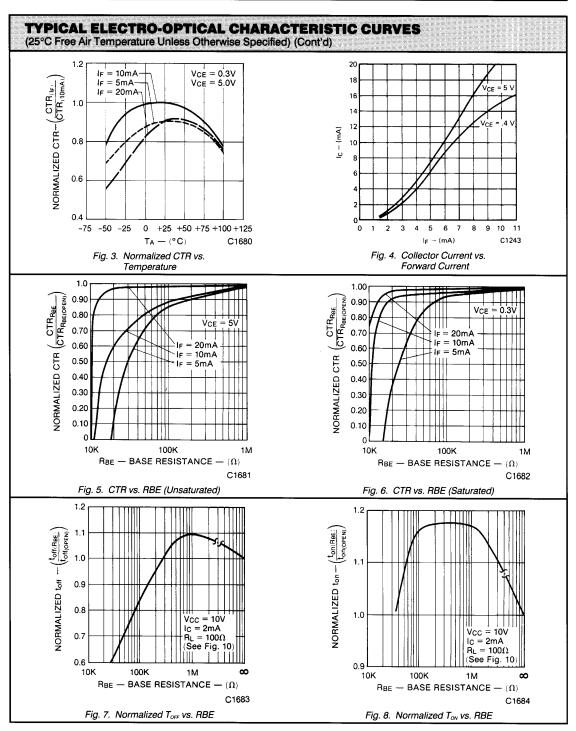
(25°C Free Air Temperature Unless Otherwise Specified) (Cont'd)

CHARACTERISTICS	SYMBOL	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
Isolation voltage all devices	V <sub>iso</sub>	5300			V <sub>RMS</sub>	$I_{HO} \le 1 \mu A$ t=1 minute
*Input to output isolation current (pulse width=8 msec) (see Note 1)	I <sub>FO</sub>					
4N35				100	$\mu$ A	V <sub>iso</sub> =3550 VAC (peak)
4N36				100	$\mu$ A	V <sub>so</sub> =2500 VAC (peak)
4N37				100	μΑ	V <sub>iso</sub> =1500 VAC (peak)
*Input to output resistance	R <sub>i-o</sub>	100			gigaohms	Input to output voltage= 500 V (see Note 1)
*Input to output capacitance	C <sub>I-O</sub>			2.5	picofarads	Input to output voltage= O V, f=1 MHz (see Note 1)

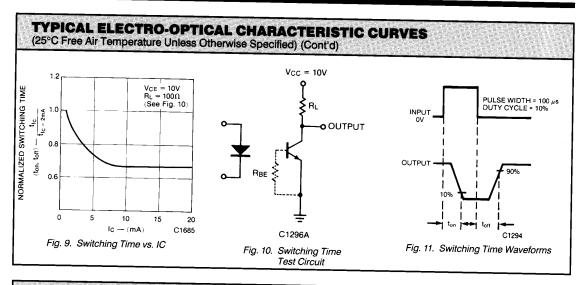
<sup>\*</sup>Indicates JEDEC registered values †Pulse test: pulse width= $300 \mu$ S,











#### NOTES

- 1. Tests of input to output isolation current resistance and capacitance are performed with the input terminals (diode) shorted together and the output terminals (transistor) shorted together.
- 2. The current transfer ratio ( $I_0/I_p$ ) is the ratio of the detector collector current to the LED input current with  $V_{ce}$  at 10 volts.
- 3. Rise time (t,) is the time required for the collector current to increase from 10% of its final value, to 90%. Fall time (t,) is the time required for the collector current to decrease from 90% of its initial value to 10%.



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